

## Nature of Magnetic Coupling between Mn Ions in As-Grown $\text{Ga}_{1-x}\text{Mn}_x\text{As}$ – Systematic Temperature and Magnetic Field Dependent XMCD –

$\text{Ga}_{1-x}\text{Mn}_x\text{As}$  is the prototypical and most well-characterized diluted magnetic semiconductor (DMS) [1]. Although many studies have been performed intensively to obtain a high Curie temperature ( $T_C$ ) exceeding room temperature, it has not been achieved yet. Because  $\text{Ga}_{1-x}\text{Mn}_x\text{As}$  is grown under thermal non-equilibrium conditions, it is difficult to avoid the formation of various kinds of defect and/or disorder, which might lead to any non-ferromagnetic component. The characterization of the non-ferromagnetic Mn ions is therefore a clue to identifying how they are related to ferromagnetic ordering and eventually to improving the ferromagnetic properties of  $\text{Ga}_{1-x}\text{Mn}_x\text{As}$  samples. However, it has been difficult to extract the above information through conventional magnetization measurement owing to the large diamagnetic response of the substrate and the unavoidable mixture of magnetic impurities. We have performed an X-ray magnetic circular dichroism (XMCD) measurement to address the problem.

X-ray magnetic circular dichroism (XMCD) is defined as the difference between X-ray absorption spectra (XAS) intensities of a ferromagnetic material for circularly polarized photons that are parallel and antiparallel to the orientation of the magnetization of the material. One can investigate and/or characterize the magnetic properties of a specific magnetic element. In the soft X-ray region (400 eV - 2000 eV), especially, the information on the spin electronic

structures can be obtained directly because the  $L_{2,3}$  absorption edge of transition metals ( $2p - 3d$ ) exists. Using the sum rules for the XAS and XMCD signal [2], the spin and orbital magnetic moments of a specific element can also be estimated quantitatively.

In the present study, in order to characterize the magnetic behaviors of substitutional Mn ( $\text{Mn}_{\text{sub}}$ ) and interstitial Mn ( $\text{Mn}_{\text{int}}$ ), we performed systematic  $T$  (sample temperature)- and  $H$  (magnetic field)-dependent XMCD studies in the Mn  $L_{2,3}$  absorption edge region of  $\text{Ga}_{1-x}\text{Mn}_x\text{As}$ . The experiments were performed at beamline **BL23SU** using the XMCD apparatus shown in Fig. 1.  $T$  and  $H$  can be scanned from  $<6$  K to room temperature and from 0 to 10 T, respectively. Recently, we have improved the XMCD measurement system for the effective measurement for a short time by installing a nonstop measurement system [3]. Using the nonstop measurement system, we can perform systematic  $T$ - and  $H$ -dependent XMCD measurements under many experimental conditions. We prepared two as-grown samples with different Mn concentrations,  $x=0.042$  and  $0.078$ , whose  $T_C$  values were  $\sim 60$  and  $40$  K, respectively. The XAS were obtained by the total electron yield mode. The measurements were carried out without surface treatment and  $H$  was applied to the sample perpendicular to the film surface.

Figure 2 shows the XAS ( $\mu^+$  and  $\mu^-$ ) in the photon energy region of the Mn  $L_3$  absorption edge and the

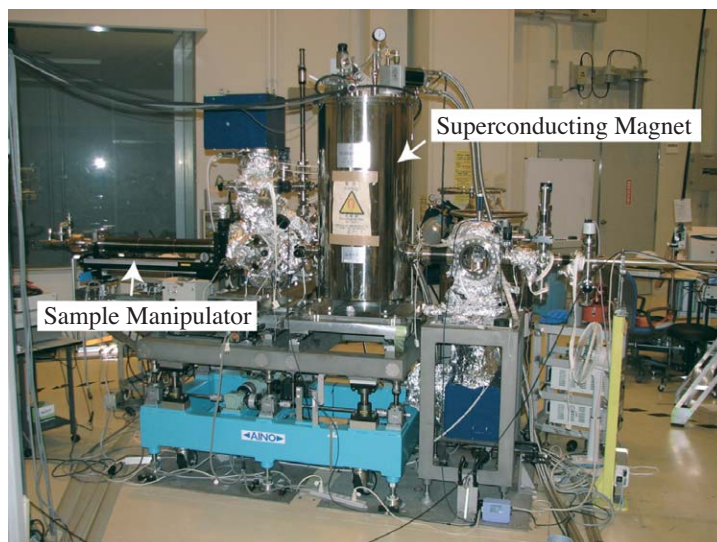


Fig. 1. XMCD apparatus of the soft X-ray beamline BL23SU.

corresponding XMCD spectra, defined as  $(\mu^+ - \mu^-)$ , at  $T = 20$  K and  $H = 0.5$  T for  $x = 0.078$ . Here,  $\mu^+$  ( $\mu^-$ ) refers to the absorption coefficient for the photon helicity parallel (anti-parallel) to the Mn  $3d$  majority spin direction. The magnitude of XMCD signals shows significant  $T$  and  $H$  dependences. Using these XAS and XMCD spectra, we applied the XMCD sum rules [2]. The spin magnetic moments ( $M_S$ ) at  $T = 20$  K and  $H = 0.5$  T are estimated to be  $M_S = 2.5 \pm 0.2$  and  $1.7 \pm 0.2$  ( $\mu_B$  per Mn) for  $x = 0.042$  and  $0.078$ , respectively.

Figure 3 shows the  $H$  dependence of  $M_S$  at several temperatures for  $x = 0.042$  [panel (a)] and  $0.078$  [panel (b)] obtained by the XMCD measurements. Above  $0.5$  T,  $M_S$  increases almost linearly as a function of  $H$ . At  $T = 20$  K, the slope (dashed lines) and  $M_S|_{H \rightarrow 0T}$  are smaller for  $x = 0.078$  than for  $x = 0.042$ , suggesting that the anti-ferromagnetic (AF) interaction becomes stronger for  $x = 0.078$  than for  $x = 0.042$ . This is reasonable because the number of  $Mn_{int}$  is expected to be larger for larger Mn concentrations. Assuming that the  $M_S$  per  $Mn_{sub}$  is  $5$  ( $\mu_B$  per Mn) and the  $M_S$  of  $Mn_{int}$  is antiparallel to that of  $Mn_{sub}$ , the ratio of  $Mn_{int}$  atoms in the intrinsic component ( $R_{int}$ ) is estimated to be  $0.26$  for  $x = 0.042$  and  $0.33$  for  $x = 0.078$  from  $M_S|_{H \rightarrow 0T}$  at  $20$  K. Therefore, this means that the number of  $Mn_{int}$  ions should be strongly related to  $T_C$ , namely,  $Mn_{int}$  ions suppress the ferromagnetic properties by ordered spins of  $Mn_{sub}$  ions.

In conclusion, we have investigated the  $T$ ,  $H$  and Mn concentration dependences of the ferromagnetism in as-grown  $Ga_{1-x}Mn_xAs$  samples by XMCD measurements. The present results indicate that the AF interaction between  $Mn_{sub}$  and  $Mn_{int}$  ions, which

is enhanced as the Mn concentration  $x$  increases, plays an important role in determining the magnetic behavior of  $Ga_{1-x}Mn_xAs$ . In addition, the number of  $Mn_{int}$  ions should be strongly related to  $T_C$ . These findings should give a valuable insight into the inhomogeneous magnetic properties of many DMS's [4].

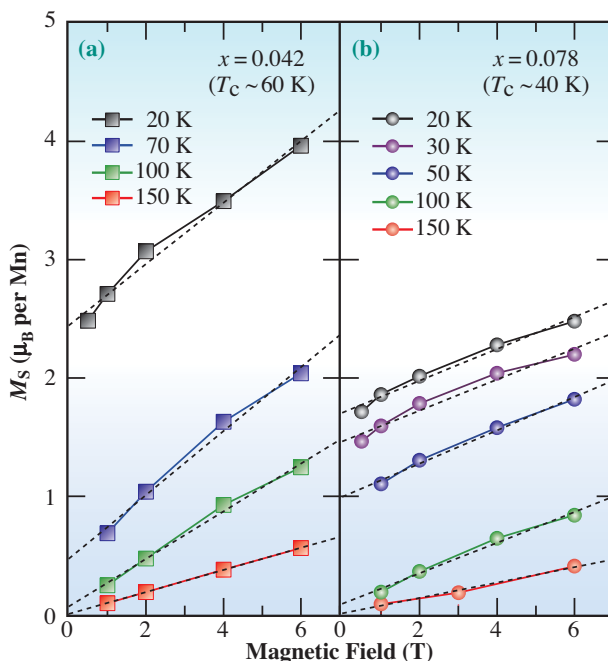


Fig. 3.  $H$  and  $T$  dependences of  $M_S$  (a)  $x = 0.042$  and (b)  $x = 0.078$ . The dashed lines show fitted straight lines above  $H = 0.5$  T.

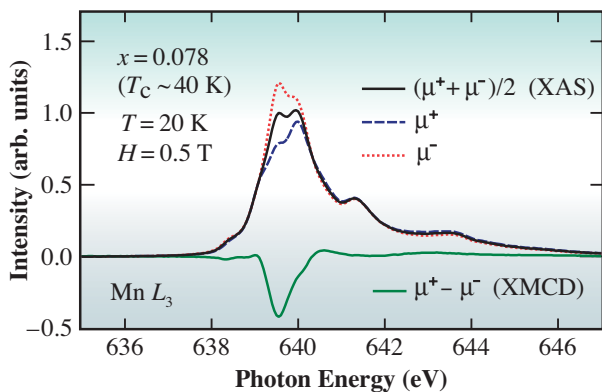


Fig. 2. XAS and XMCD spectra of  $x = 0.078$  at  $T = 20$  K and  $H = 0.5$  T in the photon energy region of the  $Mn L_3$  absorption edge.

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#### References

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